

Photoelectron spectroscopy of thin-film Yb-Si(100) structures formed by solid phase epitaxy at 800 K

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Technical Physics Letters

2004; 30(9):738-740

ARTICLE IDENTIFIERS

DOI: 10.1134/1.1804581

PMID: unavailable

PMCID: not available

JOURNAL IDENTIFIERS

LCCN: not available

pISSN: 1063-7850

eISSN: not available

OCLC ID: not available

CONS ID: not available

US National Library of Medicine ID: not available

This article was identified from a query of the SafetyLit database.